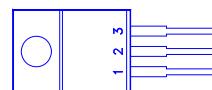
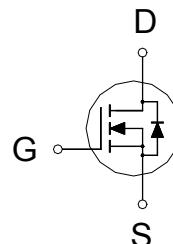


**NIKO-SEM**
**N-Channel Enhancement Mode  
Field Effect Transistor**
**P0510AT**  
TO-220  
Halogen-Free & Lead-Free
**PRODUCT SUMMARY**

$V_{(BR)DSS}$	$R_{DS(ON)}$	$I_D$
100V	5.5mΩ	143A


1. GATE  
2. DRAIN  
3. SOURCE
**ABSOLUTE MAXIMUM RATINGS ( $T_A = 25^\circ\text{C}$  Unless Otherwise Noted)**

PARAMETERS/TEST CONDITIONS		SYMBOL	LIMITS	UNITS
Drain-Source Voltage		$V_{DS}$	100	V
Gate-Source Voltage		$V_{GS}$	$\pm 25$	V
Continuous Drain Current <sup>2</sup>	$T_C = 25^\circ\text{C}$	$I_D$	143	A
	$T_C = 100^\circ\text{C}$		90	
Pulsed Drain Current <sup>1</sup>		$I_{DM}$	350	A
Avalanche Current		$I_{AS}$	36	
Avalanche Energy	$L = 1\text{mH}$	$E_{AS}$	648	mJ
Power Dissipation	$T_C = 25^\circ\text{C}$	$P_D$	227	W
	$T_C = 100^\circ\text{C}$		90	
Operating Junction & Storage Temperature Range		$T_j, T_{stg}$	-55 to 150	° C

**THERMAL RESISTANCE RATINGS**

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNITS
Junction-to-Case	$R_{\theta JC}$	0.55	62.5	°C / W
Junction-to-Ambient	$R_{\theta JA}$			

<sup>1</sup>Pulse width limited by maximum junction temperature.<sup>2</sup>Package limitation current is 111A.**ELECTRICAL CHARACTERISTICS ( $T_J = 25^\circ\text{C}$ , Unless Otherwise Noted)**

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNITS
			MIN	TYP	MAX	
<b>STATIC</b>						
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0\text{V}, I_D = 250\mu\text{A}$	100			V
Gate Threshold Voltage	$V_{GS(\text{th})}$	$V_{DS} = V_{GS}, I_D = 250\mu\text{A}$	2	3	4	
Gate-Body Leakage	$I_{GSS}$	$V_{DS} = 0\text{V}, V_{GS} = \pm 25\text{V}$			$\pm 100$	nA
Zero Gate Voltage Drain Current	$I_{DSS}$	$V_{DS} = 80\text{V}, V_{GS} = 0\text{V}$			1	$\mu\text{A}$
		$V_{DS} = 80\text{V}, V_{GS} = 0\text{V}, T_J = 125^\circ\text{C}$			10	

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Drain-Source On-State Resistance <sup>1</sup>	$R_{DS(ON)}$	$V_{GS} = 7V, I_D = 15A$	4.4	7.5	$m\Omega$
		$V_{GS} = 10V, I_D = 20A$	4	5.5	
Forward Transconductance <sup>1</sup>	$g_{fs}$	$V_{DS} = 10V, I_D = 20A$	50		S
<b>DYNAMIC</b>					
Input Capacitance	$C_{iss}$	$V_{GS} = 0V, V_{DS} = 25V, f = 1MHz$	6716		$pF$
Output Capacitance	$C_{oss}$		851		
Reverse Transfer Capacitance	$C_{rss}$		555		
Gate Resistance	$R_g$		1		
Total Gate Charge <sup>2</sup>	$Q_{g(VGS=10V)}$	$V_{DS} = 50V, I_D = 20A$	146		$nC$
	$Q_{g(VGS=7V)}$		113		
Gate-Source Charge <sup>2</sup>	$Q_{gs}$		30		
Gate-Drain Charge <sup>2</sup>	$Q_{gd}$		56		
Turn-On Delay Time <sup>2</sup>	$t_{d(on)}$	$V_{DD} = 50V,$ $I_D \approx 20A, V_{GS} = 10V, R_{GEN} = 6\Omega$	98		$nS$
Rise Time <sup>2</sup>	$t_r$		194		
Turn-Off Delay Time <sup>2</sup>	$t_{d(off)}$		170		
Fall Time <sup>2</sup>	$t_f$		88		
<b>SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS (<math>T_J = 25^\circ C</math>)</b>					
Continuous Current <sup>3</sup>	$I_S$			143	A
Forward Voltage <sup>1</sup>	$V_{SD}$	$I_F = 20A, V_{GS} = 0V$		1.2	V
Reverse Recovery Time	$t_{rr}$	$I_F = 20A, dI/dt = 100A/\mu s$	53		$nS$
Reverse Recovery Charge	$Q_{rr}$		98		$nC$

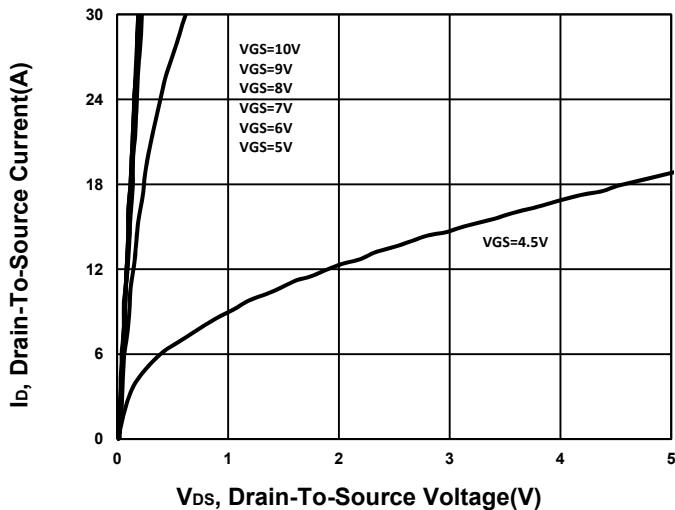
<sup>1</sup>Pulse test : Pulse Width  $\leq 300 \mu sec$ , Duty Cycle  $\leq 2\%$ .<sup>2</sup>Independent of operating temperature.<sup>3</sup>Package limitation current is 111A.

**NIKO-SEM**

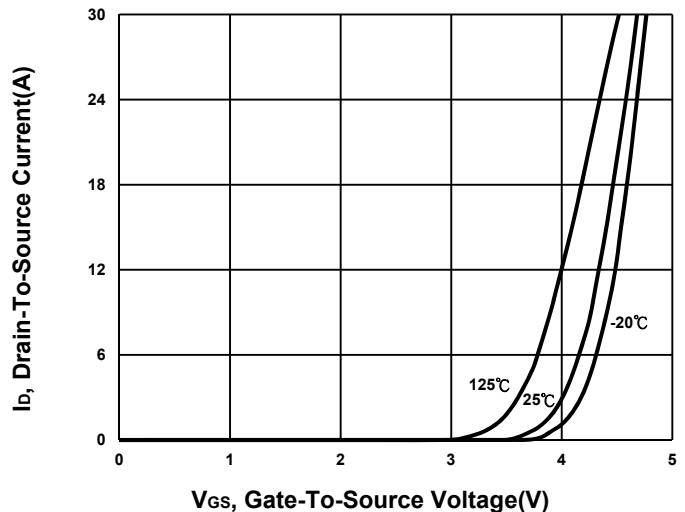
**N-Channel Enhancement Mode  
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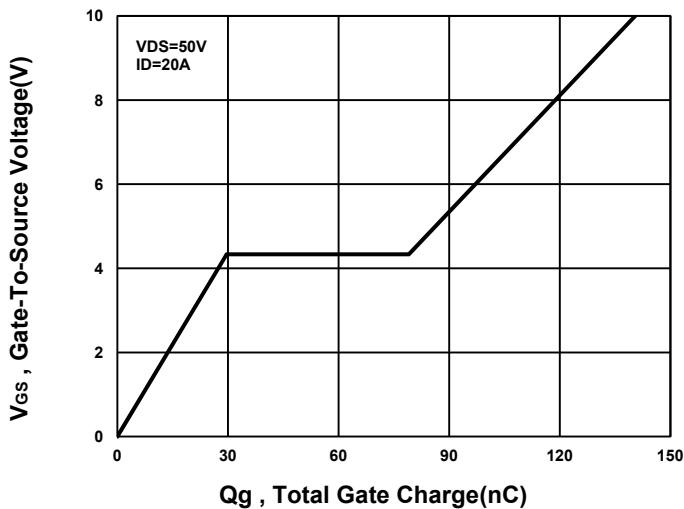
**Output Characteristics**



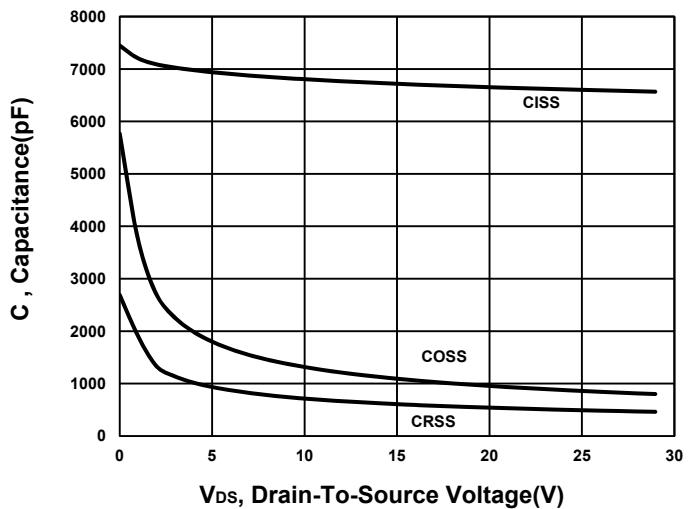
**Transfer Characteristics**



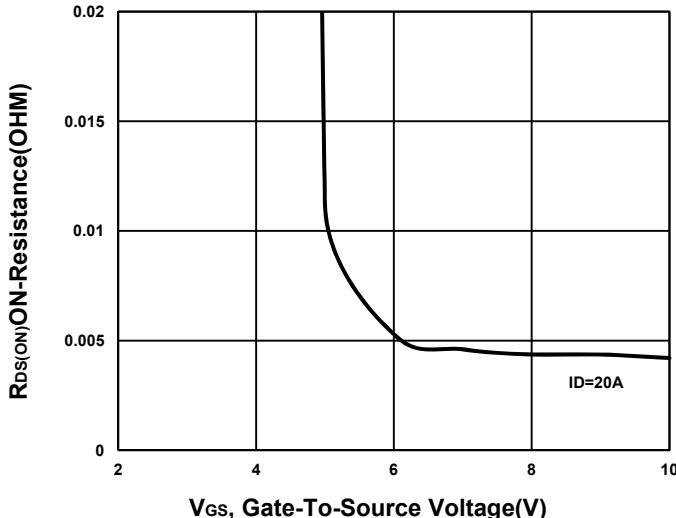
**Gate charge Characteristics**



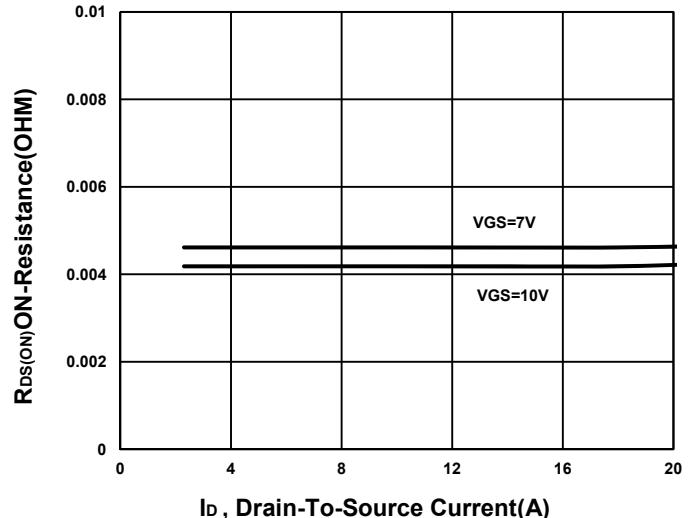
**Capacitance Characteristic**

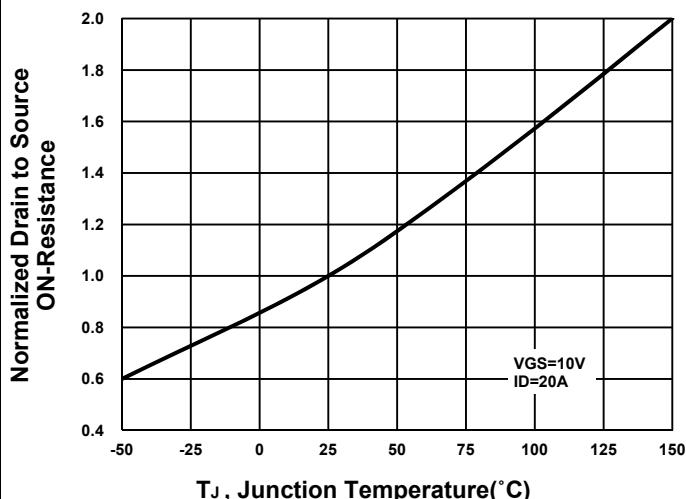
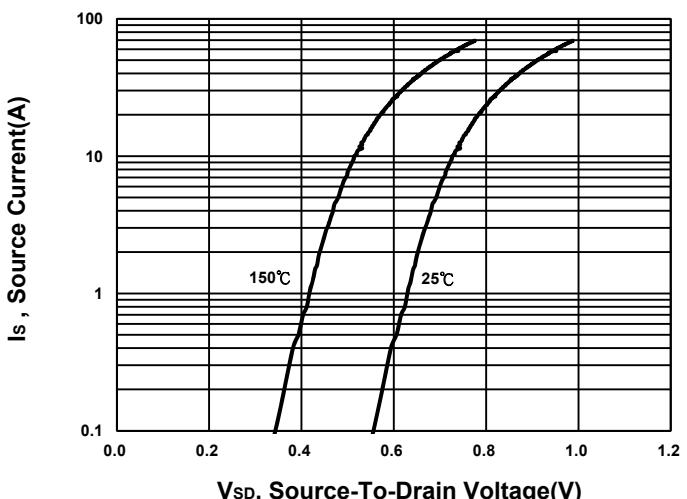
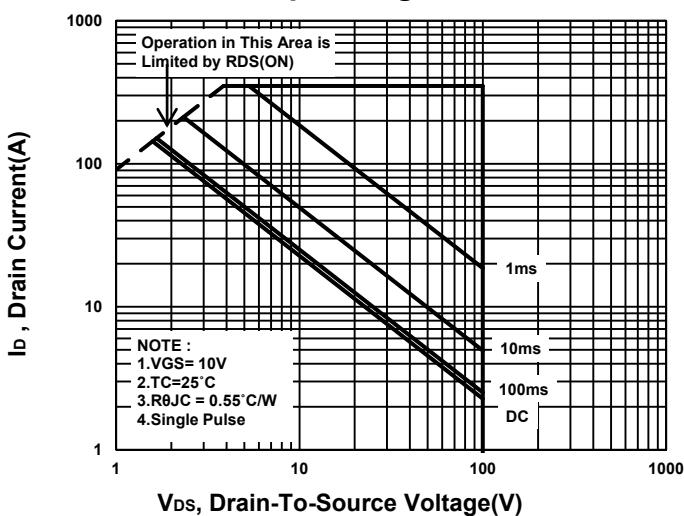
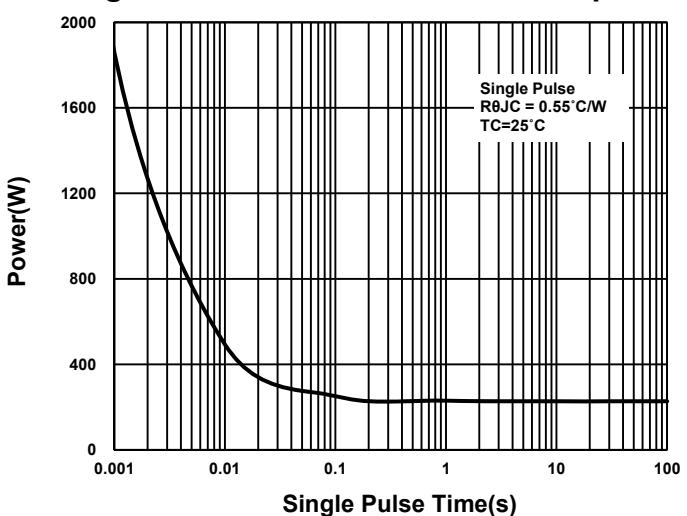


**On-Resistance VS Gate-To-Source**



**On-Resistance VS Drain Current**



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**On-Resistance VS Temperature****Source-Drain Diode Forward Voltage****Safe Operating Area****Single Pulse Maximum Power Dissipation****Transient Thermal Response Curve**